

RoHS

## 2SK2847-VB Datasheet

# N-Channel 900V (D-S) Super Junction Power MOSFET

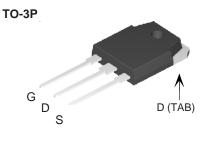
PRODUCT SUMMARY				
V <sub>DS</sub> (V) at T <sub>J</sub> max.	900			
R <sub>DS(on)</sub> at 25 °C (Ω)	$V_{GS} = 10 V$	0.75		
Q <sub>g</sub> max. (nC)	20			
Q <sub>gs</sub> (nC)	2.4			
Q <sub>gd</sub> (nC)	11			
Configuration	Single			

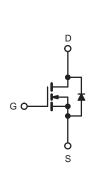
#### **FEATURES**

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (Ciss)
- · Reduced switching and conduction losses
- Ultra low gate charge (Q<sub>q</sub>)
- Avalanche energy rated (UIS)

#### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
  - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Industrial





N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> ( $T_C = 25$ °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	900	v	
Gate-Source Voltage			V <sub>GS</sub>	± 30	v	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	V <sub>GS</sub> at 10 V T <sub>C</sub> =	T <sub>C</sub> = 25 °C T <sub>C</sub> = 100 °C	- I <sub>D</sub> -	9		
	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C		7.3	А	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	28		
Linear Derating Factor				1.89	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	86	mJ	
Maximum Power Dissipation			PD	109	W	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C	
Drain-Source Voltage Slope	T <sub>J</sub> = 125 °C		dV/dt	50	V/ns	
Reverse Diode dV/dt <sup>d</sup>			av/at	3.2	v/ns	
Soldering Recommendations (Peak Temperature) <sup>c</sup>	for 10 s			300	°C	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. V<sub>DD</sub> = 50 V, starting T<sub>J</sub> = 25 °C, L = 28.2 mH, R<sub>g</sub> = 25  $\Omega$ , I<sub>AS</sub> = 3.5 A.

c. 1.6 mm from case. d.  $I_{SD} \le I_D$ , dl/dt = 100 A/µs, starting  $T_J = 25$  °C.

### 2SK2847-VB



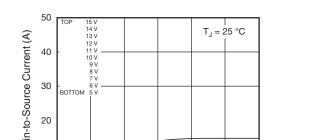
THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	72	°C/W		
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.7	0/11		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static				•	•	•	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 250 \mu\text{A}$		900	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, $I_D = 1 \text{ mA}$		-	0.65	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA		2	-	4	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA
		,	$V_{GS} = \pm 30 \text{ V}$		-	± 1	μA
		V <sub>DS</sub> =	= 900 V, V <sub>GS</sub> = 0 V	-	-	1	μΑ
Zero Gate Voltage Drain Current	I <sub>DSS</sub>		, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	10	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 6 A	-	0.75	-	Ω
Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> = 30 V, I <sub>D</sub> = 6 A		-	19	-	S
Dynamic		•		1	1	1	1
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 V,$ $V_{DS} = 100 V,$ f = 1 MHz		-	373	-	-
Output Capacitance	C <sub>oss</sub>			-	26	-	
Reverse Transfer Capacitance	C <sub>rss</sub>			-	14	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	- $V_{DS} = 0 V \text{ to } 520 V, V_{GS} = 0 V$		-	46	-	pF
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	64	-	
Total Gate Charge	Qg			-	26		
Gate-Source Charge	Q <sub>gs</sub>	$V_{GS} = 10 V$	V <sub>GS</sub> = 10 V I <sub>D</sub> = 6 A, V <sub>DS</sub> = 520 V		2.1	-	nC
Gate-Drain Charge	Q <sub>gd</sub>			-	2.8	-	
Turn-On Delay Time	t <sub>d(on)</sub>			-	26	-	- ns
Rise Time	t <sub>r</sub>	Voo	$V_{DD} = 620 \text{ V}, I_D = 6 \text{ A},$		55.7	-	
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{\rm GS} = 10$ V, $R_{\rm g} = 9.1$ $\Omega$		-	71	-	
Fall Time	t <sub>f</sub>			-	41	-	
Gate Input Resistance	R <sub>g</sub>	f = 1 MHz, open drain		-	3.5	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	7	
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	18	A
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 6 A, V <sub>GS</sub> = 0 V		-	-	1.4	V
Reverse Recovery Time	t <sub>rr</sub>	$T_{J} = 25 \text{ °C}, I_{F} = I_{S} = 6 \text{ A},$ dl/dt = 100 A/µs, V <sub>R</sub> = 400 V		-	192	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>			-	2.4	-	μC
Reverse Recovery Current	I <sub>RRM</sub>			-	11	_	A

#### Notes

a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .





#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

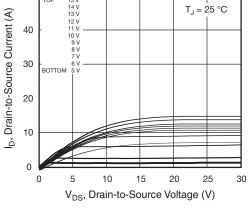


Fig. 1 - Typical Output Characteristics

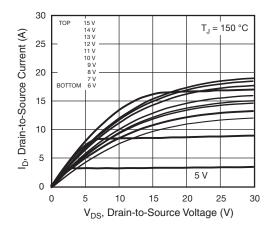


Fig. 2 - Typical Output Characteristics

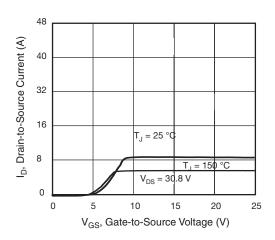


Fig. 3 - Typical Transfer Characteristics

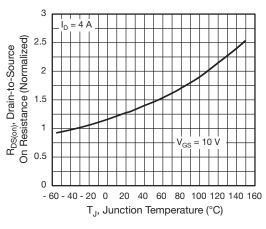


Fig. 4 - Normalized On-Resistance vs. Temperature

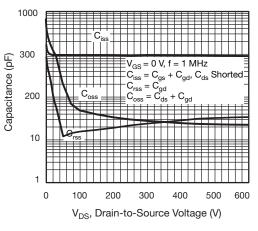


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

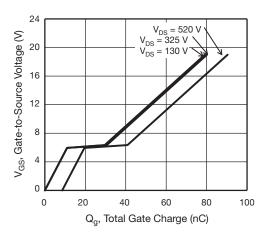


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



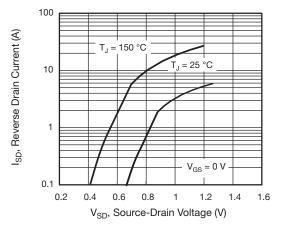


Fig. 7 - Typical Source-Drain Diode Forward Voltage

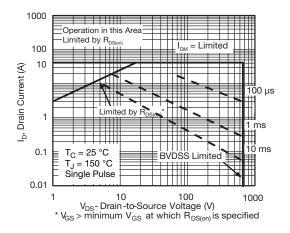


Fig. 8 - Maximum Safe Operating Area

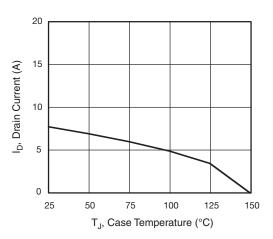


Fig. 9 - Maximum Drain Current vs. Case Temperature

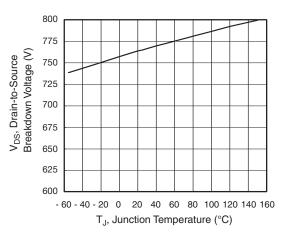


Fig. 10 - Temperature vs. Drain-to-Source Voltage

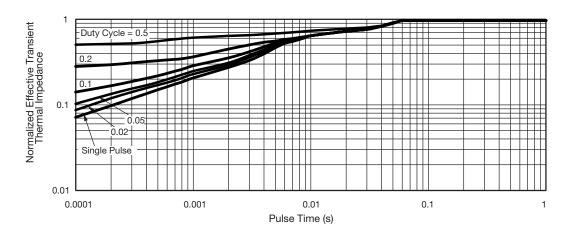


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



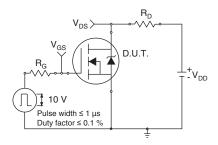


Fig. 12 - Switching Time Test Circuit

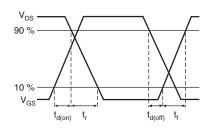


Fig. 13 - Switching Time Waveforms

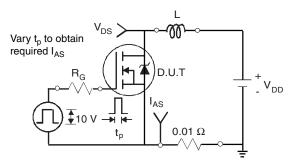


Fig. 14 - Unclamped Inductive Test Circuit

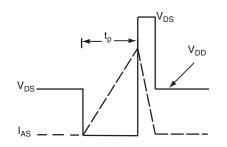


Fig. 15 - Unclamped Inductive Waveforms

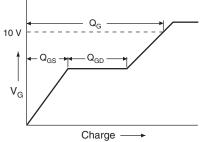


Fig. 16 - Basic Gate Charge Waveform

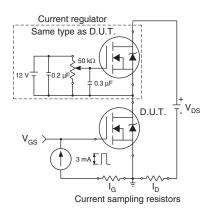
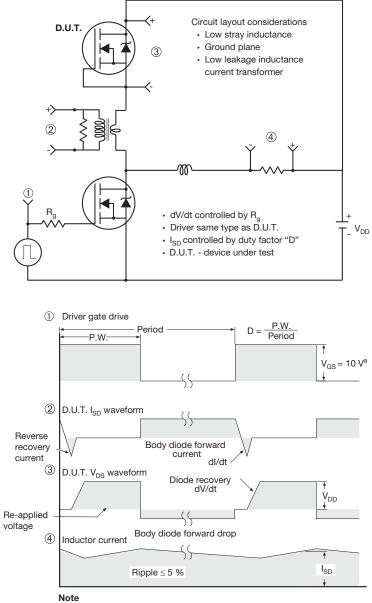


Fig. 17 - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit



a.  $V_{GS} = 5$  V for logic level devices

Fig. 18 - For N-Channel



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